

Cont. A1

This application is related to U.S. patent application serial number 09/632,080, entitled "General Purpose Shape-Based Layout Processing Scheme for IC Layout Modifications," filed on August 2, 2000.

REMARKS

The amendments indicated herein have been made to update references to related applications and to revise a portion of the Brief Description of Drawings section. It is respectfully submitted that these amendments do not add any new matter to this application.

The Examiner is invited to contact the undersigned by telephone if it is believed that such contact would further the examination of the present application.

If there are any additional charges, please charge them to our Deposit Account No. 50-1302.

Respectfully submitted,

HICKMAN PALERMO TRUONG & BECKER LLP

Dated: April 20, 2001



Edward A. Becker
Reg. No. 37,777

1600 Willow Street
San Jose, California 95125-5106
Telephone: (408) 414-1080
Facsimile: (408) 414-1076

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Washington, DC 20231

on April 20, 2001

by


Tirenna Say



MARKED UP VERSION OF REPLACEMENT SECTIONS

BRIEF DESCRIPTION OF THE DRAWINGS

Figures 9[is a]A and 9B are flow diagrams for selecting dissection points using the dissection parameters according to one embodiment.

RELATED APPLICATIONS

This application is related to U.S. patent application serial number []
09/675,582 (Attorney Docket 50275-0013), entitled "Dissection Of Corners In A Fabrication Layout For Correcting Proximity Effects," filed on September 29, 2000, invented by Christophe Pierrat and Youping Zhang.

This application is related to U.S. patent application serial number []
09/676,375 (Attorney Docket 50275-0015), entitled "Dissection Of Printed Edges From A Fabrication Layout For Correcting Proximity Effects," filed on September 29, 2000, invented by Christophe Pierrat and Youping Zhang.

This application is related to U.S. patent application serial number []
09/676,356 (Attorney Docket 50275-0016), entitled "Selection Of Evaluation Point Locations Based on Proximity Effects Model Amplitudes For Correcting Proximity Effects In A Fabrication Layout," filed on September 29, 2000, invented by Christophe Pierrat and Youping Zhang.

This application is related to U.S. patent application serial number []
09/728,885 (Attorney Docket 50275-0017), entitled "Displacing Edge Segments On A Fabrication Layout Based on Proximity Effects Model Amplitudes For Correcting Proximity

Effects,” filed on [] December 1, 2000, invented by Christophe Pierrat and Youping Zhang.

This application is related to U.S. patent application serial number 09/130,996, entitled “Visual Inspection and Verification System,” filed on August 7, 1998.

This application is related to U.S. patent application serial number 09/153,783, entitled “Design Rule Checking System and Method,” filed on September 16, 1998.

This application is related to U.S. patent application serial number 09/544,798, entitled “Method and Apparatus for a Network Based Mask Defect Printability Analysis System,” filed on April 7, 2000.

This application is related to U.S. patent application serial number 09/154,415, entitled “Data Hierarchy Layout Correction and Verification Method and Apparatus,” filed on September 16, 1998.

This application is related to U.S. patent application serial number 09/154,397, entitled “Method and Apparatus for Data Hierarchy Maintenance in a System for Mask Description,” filed on September 16, 1998.

This application is related to U.S. patent application serial number 09/632,080, entitled “General Purpose Shape-Based Layout Processing Scheme for IC Layout Modifications,” filed on August 2, 2000.